

## Monitor, detect, and eliminate wire strip defects

### Conductor Touch:

Is the root cause of common crimp defects. The result of conductor touch during insulation removal can be cut, nicked, pulled, torn, or scraped conductors. These quality defects are hidden inside the terminal crimp.

### Causes of Conductor Touch:

- Wire quality – variation in concentricity.
- Wire type – thin wall, insulation material.
- Machine setup.
- Cutting/Stripping blade quality.
- Capability of the wire strip control unit.
- Stripping blade incompatibility.
- Combination of the above.

### CQS for Conductor Touch

CQS Electrodes inject a signal onto the wire which is monitored during the wire stripping operation. Incidence(s) of conductor touch are detected during production. CQS algorithms analyze the conductor touch relative to control parameters for control of potential wire strip defects.

### CQS Capabilities

Detection of conductor touch conditions that causes crimp defects:

- One or more missing or torn strands.
- Pulled strands
- Nicked strands
- Scraped strands



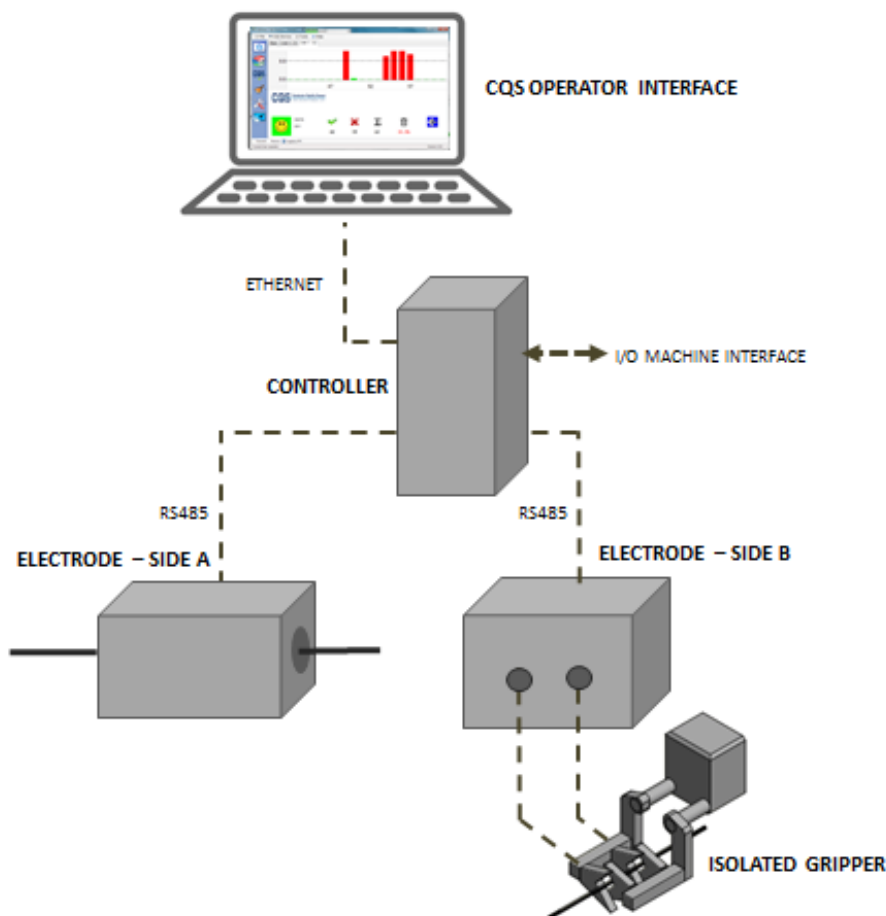
\*\* Works equally for copper and aluminum wire

## Quick Facts

MODEL	APPLICATION
CQS	Automatic Crimp to Crimp Automatic Cut and Strip

## Operator Interface

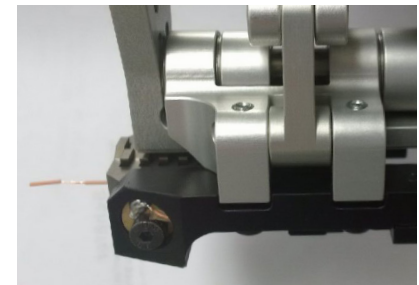
- CQS Windows compatible application software for process monitoring of conductor touch



Electrode - Side A



Electrode - Side B



Isolated Gripper



Controller

**Adaptable to a wide range of wire processing machines**

Patents Pending

## About OES Technologies

OES Technologies products and technologies are developed specifically for the wire processing industry to monitor and inspect 100% of parts produced during the manufacturing process, and prevent part defects from entering the supply chain. OES's dedication to innovation enables them to deliver a steady stream of cutting-edge technologies that meet the exacting demands of this ever-changing market.